

- LTI Systems

- Linearity: $L(aX_1 + bX_2) = aL(X_1) + bL(X_2)$
- Time Invariant: $L(X(t-\tau)) = Y(t-\tau)$
- Sinusoidal: $\sin(\omega t) = \frac{1}{2j}(e^{j\omega t} - e^{-j\omega t})$
- Complex exponential: $e^{j\omega t}$ is eigenfunction of LTI
- $H(\omega)$ is eigenvalue: $L(e^{j\omega t}) = H(\omega)e^{j\omega t} = |H(\omega)|e^{j(\omega t + \phi)}$
- $H(\omega)$ for steady state, $H(s)$ for transient response $\rightarrow e^{st}$
- Dirac Delta $\delta(t)$
 - $x(t) = \int \delta(t-\tau)x(\tau)d\tau$ // sifting prop
 - $x(t) = \int x(\tau)\delta(t-\tau)d\tau$
- Impulse Response $h(t) = L(\delta(t))$
- convolution: $L(x(t)) = y(t) = h(t) * x(t) = \int_{-\infty}^{\infty} h(t-\tau)x(\tau)d\tau$
- Linearity super useful
- Laplace Transform: $H(s) = \int_{-\infty}^{\infty} h(t)e^{-st}dt$
- $Y(s) = H(s)X(s)$
- Fourier Series: $x(t) = \sum_{n=-\infty}^{\infty} C_n e^{j2\pi n t}$
- FT: $X(\omega) = \int_{-\infty}^{\infty} x(t)e^{-j\omega t}dt$

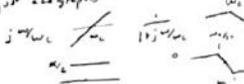
- AC Circuits / Analysis

- Transfer Functions
- Impedance important
- Transfer Impedance Amplifier (TIA) - circuit to voltage
- $Z(\omega) = \frac{V}{I}$
- Admittance $Y(\omega) = I/V$
- TF Block/Zeros
- $H(\omega) = G_c(j\omega)^k \frac{\prod(1-j\omega\tau_z)}{\prod(1-j\omega\tau_p)}$ + poles

- Phasors

- $Z_C = j\omega L$, $Z_L = j\omega L$, $Z_R = R$
- $R_1 || R_2 = \frac{R_1 R_2}{R_1 + R_2}$
- Thevenin Eqn:  - short V, open I, measure R, shorts output, measure current apply current source
- Norton Eqn:  - current apply current source
- RLC circuit
 - resonance - impedance minimum voltage
 - voltage gain, but not power
 - $Q = \frac{\omega L}{R} = \frac{1}{\omega C R}$
 - high Q good for signal processing

- Bode Plot

- just all graphs
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- Power

- $P_{avg} = \frac{1}{T} \int p(t)dt = \frac{1}{T} \int v(t)i(t)dt$ // nonlinear
- Input Impedance - Z_{in} is good from input
- Output Impedance - impedance to give max power
- Maxwell's Division Eq: $\frac{dE}{dx} = \frac{p(x)}{E}$
- Gauss law $\oint E \cdot dS = \frac{Q_{enc}}{\epsilon_0}$
- $E = -\frac{dV}{dx}$
- 1D Poisson Eqn: $\frac{d^2 V(x)}{dx^2} = -\frac{\rho(x)}{\epsilon_0}$

- Inhomogeneous

- Ohm's Law (resistor) $V = IR$
- $J = \sigma E$; $\frac{I}{A} = \sigma \frac{V}{L}$; $V = \frac{L}{\sigma A} I$ // IR
- current by + and - charge carriers
- $\sigma = q^2 \left(\frac{n \tau_e}{m^*} + \frac{p \tau_h}{m} \right)$ (ideal semiconductor)
- free carriers (electrons and holes) movement & impurities
- values and evaluation band (band gap)
- free e^- if much thermal energy (> band gap)
- Holes for intrinsic semiconductor
- Recombination: $e^- + hole (p^+) \rightarrow$
- Thermal Equilibrium
 - generation = recombination
 - $n_0 = p_0$ $n_0 p_0 = n_i^2$ law of Mass Action
 - $n_0 \approx 10^{16} cm^{-3}$; $10^{10} cm^{-3}$
 - $n_i \approx e^{-E_g/2kT}$ // $E_g \approx$ band gap
- Doping
 - Group V (Phosphorus) (N-type)
 - extra e^-
 - $p = -qN_A + qn_0 + qN_D \approx 0$ // neutral
 - if $N_D \gg n_i$, $n_0 = N_D$ (N-type)
 - if $N_A \gg n_i$, $p_0 = N_A$ (P-type)
 - Compensation - if $N_D - N_A \gg n_i$, $n_0 = N_D - N_A$; if $N_A - N_D \gg n_i$, $p_0 = N_A - N_D$ if $N_D > N_A$

- Drift Current

- proportional to applied field E
- Drift Current: $J = qn\mu E + qp\mu E$ // combination gradient
- Einstein Relation: $D_n = \frac{kT}{q} \mu_n$ // mobility
- Total current: $J = J_{diff} + J_{drift} = qn\mu E + qD_n \frac{dn}{dx}$

- IC stuff

- IC resistor - poly film resistor
- 1st of process, capacitance
- $R = \frac{L}{W \sigma} = R_0 \left(\frac{L}{W} \right)$
- Backlash stuff - E direction, data placement
- IC Cap: $C = \frac{\epsilon A}{d}$, $Q = CV$
 - nonlinear cap $Q = f(V)$
 - small signal $G = f'(V)$ // $\frac{C}{V}$

- PN Equilibrium

- $V_{bi} = \frac{kT}{q} \ln \left(\frac{N_A N_D}{n_i^2} \right)$
- $\phi_n = V_{bi} \ln \left(\frac{n}{n_i} \right)$, $\phi_p = -V_{bi} \ln \left(\frac{p}{n_i} \right)$
- Transition Region - x_p to x_n
- depletion Approximation - 0 free carriers
- $E = 0$ within region
- $x_n = \sqrt{\frac{2\epsilon_s \phi_n}{q N_D}}$, $x_p = \sqrt{\frac{2\epsilon_s \phi_p}{q N_A}}$
- $X_{do} = \sqrt{\frac{2\epsilon_s \phi_{bi}}{q} \left(\frac{1}{N_A} + \frac{1}{N_D} \right)}$, $\phi_{bi} = V_{bi} \ln \left(\frac{N_A N_D}{n_i^2} \right)$
- not a battery bc contact potential
- Reverse Bias $V_0 < 0$, x_n to $x_p \Rightarrow \phi_n - V_0$, scale $\sqrt{1 - \frac{V_0}{V_{bi}}}$
- $Q = -q N_A x_p = q \int_{-x_p}^0 n dx$
- $C_j = \frac{q N_A x_p}{2 \phi_n \sqrt{1 - \frac{V_0}{V_{bi}}}} = \frac{C_{j0}}{\sqrt{1 - \frac{V_0}{V_{bi}}}}$, $C_{j0} = \frac{\epsilon_s}{X_{do}}$

- PN Current

- $I_D = I_S (e^{\frac{qV}{kT}} - 1)$
- $\frac{dAP}{dx} = -q p_n n_p$ or $AP = P_0$ constant above equilibrium
- $= -\frac{dP}{dx}$ minority carrier flux
- $\frac{dJ_p}{dx} = q \frac{dAP}{dx}$ // if current above accumulation, C change
- $J_p = q D_p \frac{dAP}{dx}$ (diffusion current from bulk)
- $\frac{d^2 AP}{dx^2} = \frac{dP}{D_p \tau_p} = \frac{dP}{L_p^2}$ $L_p = \sqrt{D_p \tau_p}$ (diffusion length)
- $I_D \approx \frac{q V_D}{kT} = q_0 V_D$ // small signal model, forward bias

- MOS Capacitor

- $V_{GS} = 0V$, $V_{DS} = 0V$, $\phi_p = -\frac{kT}{q} \ln \left(\frac{N_A}{n_i} \right)$
- $\phi_{p0,ms} = \frac{kT}{q} \ln \left(\frac{N_A n_p}{n_i^2} \right)$
- $V_{GS} = 0$, $V_{DS} = -(\phi_{n0} - \phi_p)$
- Accumulation $V_{GS} > V_{FB}$, // p-type $Q_{GS} = C_{ox}(V_{GS} - V_{FB})$
- Depletion $V_{GS} < V_{FB}$, $V_{GS} > V_{FB}$ // depletion region
- Inversion $V_{GS} > V_T$, $V_{GS} > V_T$ // n-type to n-type, $p \rightarrow n$
- $n_s = n_i e^{\frac{q\phi_s}{kT}} = N_D$, $\phi_s = -\phi_p$
- $V_{TH} = V_{FB} - 2\phi_p + \frac{1}{C_{ox}} \sqrt{2q\epsilon_s N_A (-2\phi_p)}$
- $\epsilon V_{TH} = \epsilon V_{FB} - 2\phi_p + \frac{Q_{dep}}{C_{ox}}$
- $C_{ox} = C_{ox} = \frac{\epsilon_{ox}}{t_{ox}}$
- Accumulation: $C_{ox} \frac{1}{1}$
- Depletion: $\frac{1}{1} C_{ox}$
- Inversion: $\frac{1}{1} C_{ox}$

- E-field

- $E = \frac{V}{d}$
- $C_{ox} = C_{ox} = \frac{\epsilon_{ox}}{t_{ox}}$
- Accumulation: $C_{ox} \frac{1}{1}$
- Depletion: $\frac{1}{1} C_{ox}$
- Inversion: $\frac{1}{1} C_{ox}$

